

Ultra-Fast recovery rectifier diode in bare die form

Rev 1.0 27/12/22

Features:

- Low leakage current
- High forward surge current capability
- Low forward voltage drop
- Robust construction
- High reliability tested grades.

Ordering Information

The following part suffixes apply:

- No suffix MIL-STD-750 /2073 Visual Inspection
- "H" MIL-STD-750 /2073 Visual Inspection + MIL-PRF-38534 Class H LAT
- "K" MIL-STD-750 /2073 Visual Inspection
 + MIL-PRF-38534 Class K LAT

LAT = Lot Acceptance Test.

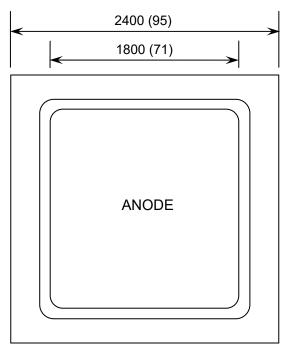
For further information on LAT process flows see below.

www.siliconsupplies.com\quality\bare-die-lot-qualification

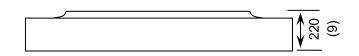
Supply Formats:

- Default Die in Waffle Pack (100 per tray capacity)
- Sawn Wafer on Tape By specific request
- Unsawn Wafer By specific request
- With additional electrical selection By specific request

Die Dimensions in µm (mils)



CHIP BACKSIDE IS CATHODE



Mechanical Specification

Die Size (Unsawn)	2400 x 2400 94.49 x 94.49	µm mils	
Anode Pad Size	1800 x 1800 70.87 x 70.87	µm mils	
Die Thickness	220 (±20) 8.66 (±0.79)		
Top Metal Composition	Al 7.5µm		
Back Metal Composition	Ti/Ni/Ag		





200V 8A 25ns Rectifier – MURC820

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Absolute Maximum Ratings	1 T _J = 25°C unless otherwise stated
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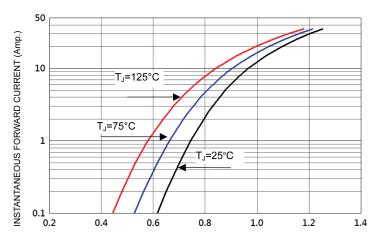
PARAMETER	SYMBOL	VALUE	UNIT	
Peak Repetitive Reverse Voltage	V _{RRM}	200		
Working Peak Repetitive Reverse Voltage	V _{RWM}		V	
DC Blocking Voltage	V _R			
RMS Reverse Voltage	V _{R (RMS)}	140	V	
Average Forward Rectified Current, $T_J = 150^{\circ}C$	I _{F(AV)}	8	A	
Peak Repetitive Forward Current ²	I _{FM}	16	A	
Non-Repetitive Peak Forward Surge Current ³	IFSM	125	A	
Operating Junction temperature	TJ	-55 to 175	°C	
Storage Temperature Range	T _{STG}	-65 to 175	°C	

Electrical Characteristics T_J = 25°C unless otherwise stated

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNIT
Maximum Instantaneous Forward Voltage ⁴	I _F = 8A, T _J = 25°C	-	0.93	0.975	V	
	I _F = 8A, T _J = 125°C	-	0.80	-	V	
Maximum Instantaneous Reverse Leakage Current ⁴	V _{RRM} = 200V, T _J = 25°C	-	0.01	0.05	μA	
		V _{RRM} = 200V, T _J = 125°C	-	1.5	10	
Reverse Recovery Time	trr	I _F = 0.5A, I _R = 1.0A, I _{rr} = 0.25A	-	-	25	ns
Junction Capacitance	CJ	V _R = 4V, f = 1.0MHz	-	52	-	pF

1. Operation above the absolute maximum rating may cause device failure. Operation at the absolute maximum ratings, for extended periods, may reduce device reliability. **2.** V_R = 200V, Square Wave, 20kHz Pulse Width = 3.8ms **3.** Surge applied at rated load conditions halfwave, single phase, 60Hz **4.** Pulse Test: Pulse Width = 300s, Duty Cycle ≤ 2.0%

Typical Characteristics T_J = 25°C unless otherwise stated



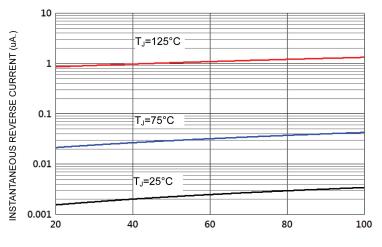
FORWARD VOLTAGE (V) FIGURE 1. Forward Voltage Characteristics







Rev 1.0 27/12/22



PERCENT OF RATED PEAK REVERSE VOLTAGE (%)

FIGURE 2. Reverse Current Versus Reverse Voltage

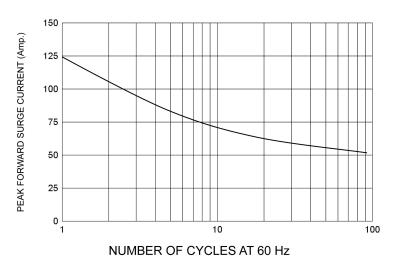


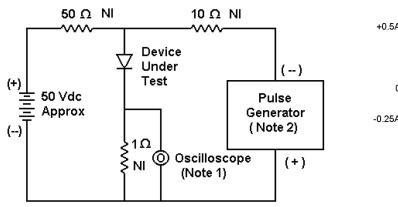
FIGURE 3. Peak Forward Surge Current Versus Cycles at 60 Hz

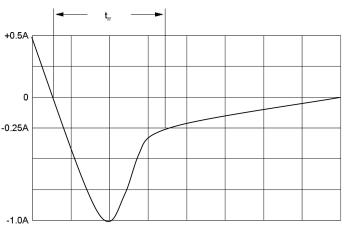




Typical Characteristics Continued T_J = 25°C unless otherwise stated

Rev 1.0 27/12/22





Notes:

1. Rise Time = 7 ns max. Input Impedance =1 M Ω , 22 pF 2. Rise Time = 10 ns max. Input Impedance = 50 Ω

Set time base for 10/20 ns/cm



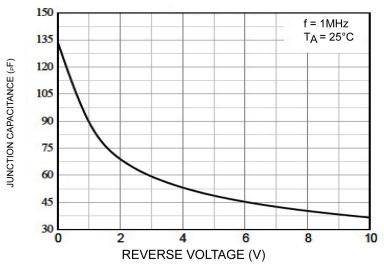


FIGURE 5. Typical Junction Capacitance

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